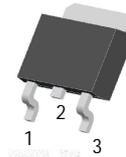




## 40N10 N-Channel Power MOSFET

$V_{(BR)DSS}$	$R_{DS(on)MAX}$	$I_D$
100V	17mΩ@10V	40A

TO-252



1. GATE
2. DRAIN
3. SOURCE

### DESCRIPTION

This advanced high voltage MOSFET is designed to stand high energy in the avalanche mode and switch efficiently. This new high energy device also offers a drain-to-source diode fast recovery time.

Designed for high voltage, high speed switching applications such as power supplies, converters, power motor controls and bridge circuits.

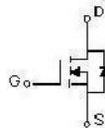
### FEATURES

- High density cell design for ultra low  $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high  $E_{AS}$
- Special process technology for high ESD capability
- Excellent package for good heat dissipation

### APPLICATIONS

- Hard switched and high frequency circuits
- Uninterruptible power supply
- Power switching application

### EQUIVALENT CIRCUIT



### MAXIMUM RATINGS ( $T_a=25^\circ\text{C}$ unless otherwise noted )

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	100	V
Gate-Source Voltage	$V_{GS}$	±20	V
Continuous Drain Current	$I_D$	40	A
Pulsed Drain Current	$I_{DM}$	160	A
Single Pulsed Avalanche Energy	$E_{AS}^{(1)}$	320	mJ
Power Dissipation	$P_D$	1.25	W
Thermal Resistance from Junction to Ambient	$R_{\theta JA}$	100	$^\circ\text{C/W}$
Junction Temperature	$T_J$	150	$^\circ\text{C}$
Storage Temperature Range	$T_{stg}$	-55 ~ +150	$^\circ\text{C}$
Lead Temperature for Soldering Purposes(1/8" from case for 10s)	$T_L$	260	$^\circ\text{C}$

(1).  $E_{AS}$  condition:  $V_{DD}=50\text{V}$ ,  $L=0.5\text{mH}$ ,  $R_G=25\Omega$ , Starting  $T_J = 25^\circ\text{C}$

$T_a=25\text{ }^{\circ}\text{C}$  unless otherwise specified

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Off characteristics</b>						
Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	100			V
Zero gate voltage drain current	$I_{DSS}$	$V_{DS} = 100V, V_{GS} = 0V$			1	$\mu A$
Gate-body leakage current	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA
<b>On characteristics (note1)</b>						
Gate-threshold voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	2.7	4	V
Static drain-source on-state resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 28A$		14	17	m $\Omega$
Forward transconductance	$g_{FS}$	$V_{DS} = 25V, I_D = 28A$	32			S
<b>Dynamic characteristics (note 2)</b>						
Input capacitance	$C_{iss}$	$V_{DS} = 30V, V_{GS} = 0V,$ $f = 1MHz$		3400		pF
Output capacitance	$C_{oss}$			290		
Reverse transfer capacitance	$C_{rss}$			221		
<b>Switching characteristics (note 2)</b>						
Total gate charge	$Q_g$	$V_{DS} = 30V, V_{GS} = 10V,$ $I_D = 30A$		94		nC
Gate-source charge	$Q_{gs}$			16		
Gate-drain charge	$Q_{gd}$			24		
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 30V, V_{GS} = 10V, R_G =$ $2.5\Omega, I_D = 2A, R_L = 15\Omega$		15		ns
Turn-on rise time	$t_r$			11		
Turn-off delay time	$t_{d(off)}$			52		
Turn-off fall time	$t_f$			13		
<b>Drain-Source Diode Characteristics</b>						
Drain-source diode forward voltage(note1)	$V_{SD}$	$V_{GS} = 0V, I_S = 28A$			1.2	V
Continuous drain-source diode forward current	$I_S$				40	A
Pulsed drain-source diode forward current	$I_{SM}$				160	A

Notes:

1. Pulse Test : Pulse Width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$ .
2. Guaranteed by design, not subject to production.

